

<div data-bbox="113 136 332 367"> </div>		Docket Number (Optional) P0387	Application Number 10/789,336
		Applicant(s) Erwan Le Roy et al	
		Filing Date 02/27/2004	Group Art Unit na
<div data-bbox="121 283 235 430"> EXAMINER INITIAL AC </div> <div data-bbox="373 283 1055 325"> OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) </div>			
<div data-bbox="308 325 1461 409"> E. I. Cole Jr., C. R. Bagnell, Jr., B. Davies, A. Neacsu, W. Oxford, S. Roy, and R. H. Propst, "A Novel Method for Depth Profiling and Imaging of Semiconductor Devices Using Capacitive Coupling Voltage Contrast", J. Appl. Phys, 62(12), 15 December 1987, pp 4909-4915 </div>			
EXAMINER 		DATE CONSIDERED 6/5/05	
<small>*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>			